has at least one signal output (OUT), at least one switching element (E1, E2) and at least one circuit unit (SCH),

wherein

the integrated circuit (IC) has a control unit (ST) which is linked to the signal output (OUT) for testing the potential at the signal output (OUT), and

the control unit (ST) is linked to at least one switching element (E1, E2), and

the input of the switching element (E1, E2) is linked to an output of the circuit unit (SCH), and

the output of the switching element (E1, E2) is linked to the signal output (OUT).

17. (new) Circuit arrangement according to claim 16,

wherein

the control unit (ST) for adapting the signals to be tested to the potential of the signal output (OUT) contains an amplifier (LE1, LE2), and

the input of the amplifier (LE1, LE2) is linked to the output of a circuit unit (SCH1),

the output of the amplifier (LE1, LE2) is linked to the input of the switching element (E1, E2),

the control unit (ST) contains at least two comparators (I1, I2 and I3, I4) which form a window discriminator,

and has a logic gate (L1, L2) for performing a logic operation on the test signals (SW1, SW2) and at least one more signal (OS) of the circuit unit (SCH),

the input of the window discriminator is linked to the